



Growth of $\text{Al}_x\text{Ga}_{1-x}\text{N}$ Layers on GaN Substrates Using Halide Vapor Phase Epitaxy Technology: Road To Novel Nitride Substrates

A. Jaroszynska¹, K. Sierakowski¹, T. Sochacki¹, P. Sadovyi¹, R. Kucharski¹,
K. Grabianska¹, R. Czernecki¹ and M. Bockowski¹

¹ Institute of High Pressure Physics Polish Academy of Sciences, Warsaw, Poland,
e-mail: arianna.jaroszynska@unipress.waw.pl

Outline

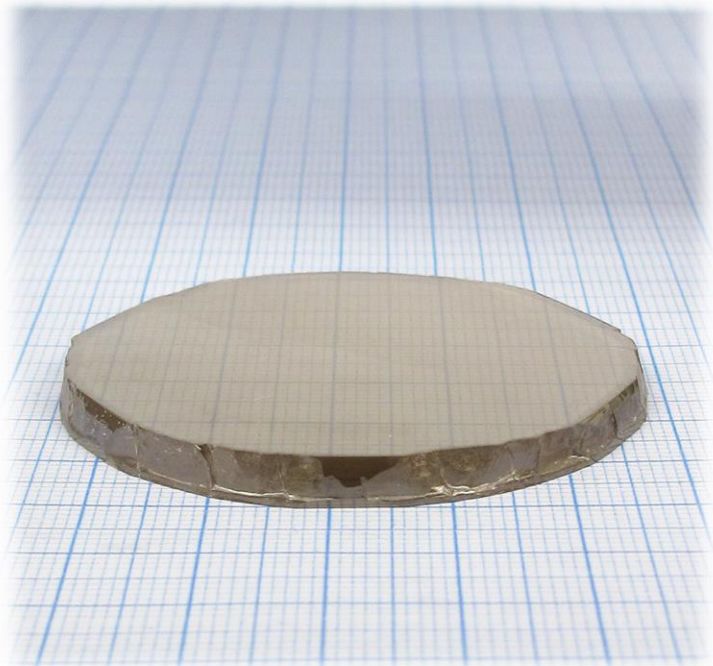
- **Introduction**
 - $\text{Al}_x\text{Ga}_{1-x}\text{N}$ substrates & applications
 - Challenges of growing $\text{Al}_x\text{Ga}_{1-x}\text{N}$
- **Experimental setup**
- **Results**
 - Optimization of growth process parameters
 - Influence of misorientation
- **Summary**



Introduction

$\text{Al}_x\text{Ga}_{1-x}\text{N}$ substrates

GaN



<http://unipress.waw.pl/>

Halide Vapor Phase Epitaxy

Ammonothermal (Acidic/Basic)

Na-Flux

$\text{Al}_x\text{Ga}_{1-x}\text{N}$

No commercially
available
free-standing
 $\text{Al}_x\text{Ga}_{1-x}\text{N}$ crystal

AlN

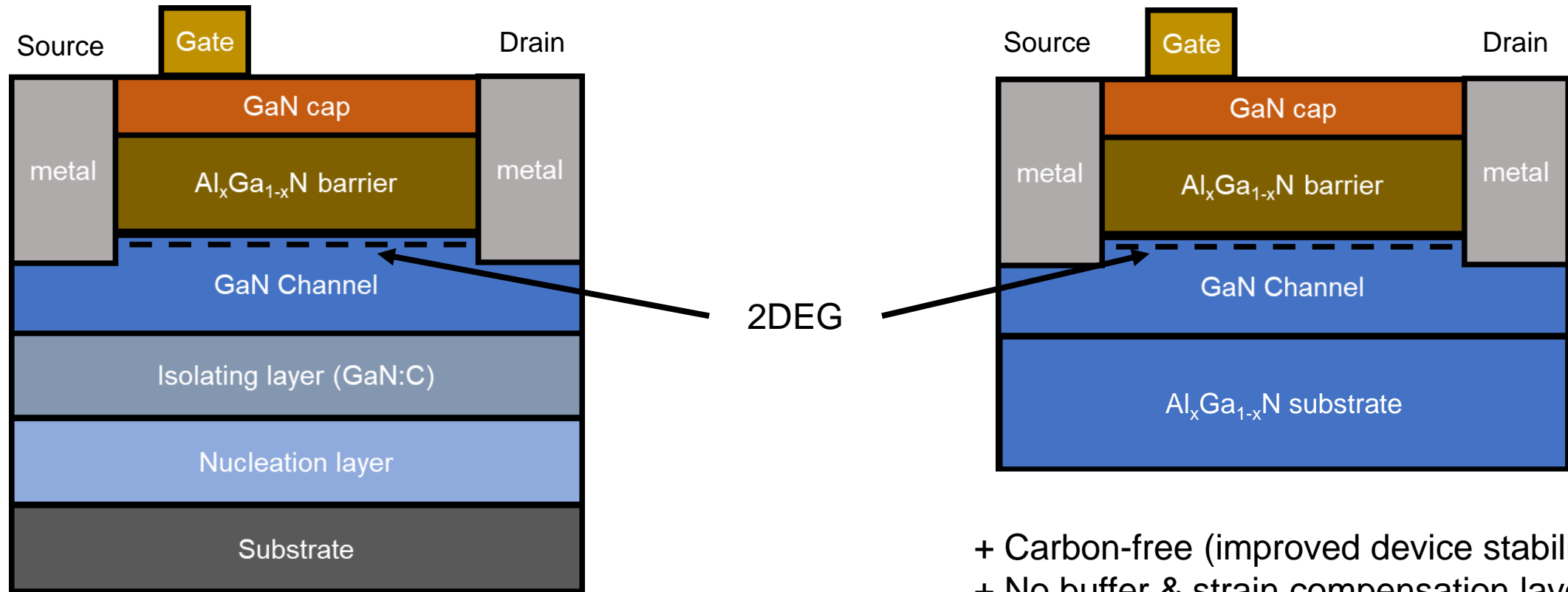


www.hexatechinc.com

Halide Vapor Phase Epitaxy

Physical Vapor Transport

High Electron Mobility Transistors (HEMT)



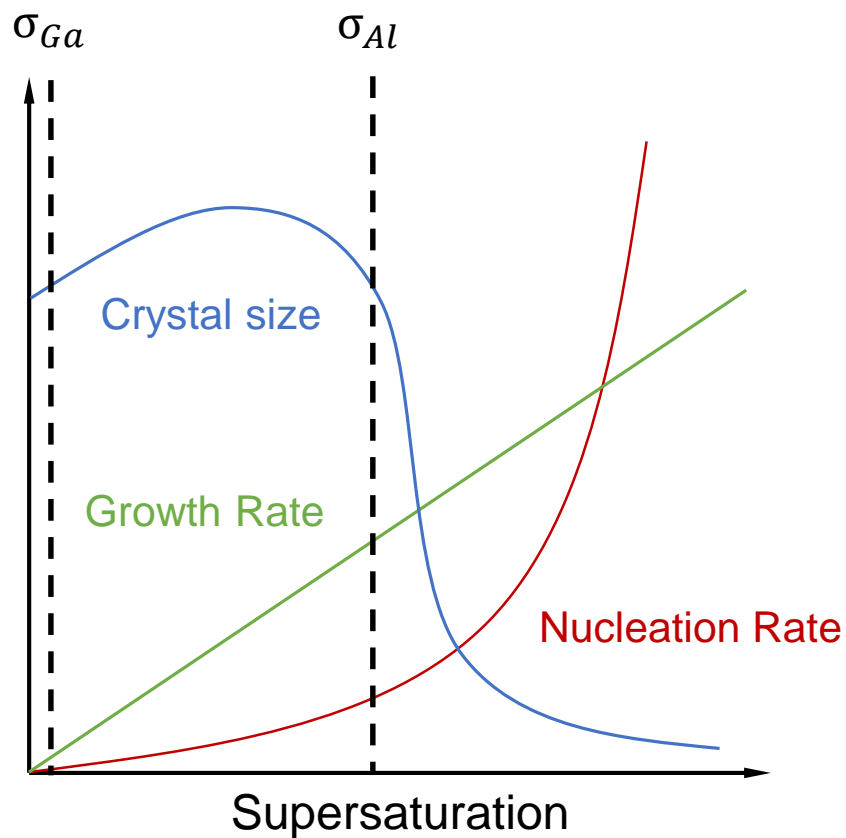
Tirado et al., *Semiconductor Science and Technology*. 20. 864. (2005)

+ Carbon-free (improved device stability)
 + No buffer & strain compensation layers
 (smaller vertical size)

Zagni et al., *Phys. Stat. Sol. A* **217** 1900762 (2020)

Challenges of growing $\text{Al}_x\text{Ga}_{1-x}\text{N}$

Optimal conditions for HVPE
GaN and AlN growth



$$\sigma_{Ga} = \frac{P_{GaCl}^{\circ} - P_{GaCl}}{P_{GaCl}}$$

$$\sigma_{Al} = \frac{P_{AlCl_3}^{\circ} - P_{AlCl_3}}{P_{AlCl_3}}$$

σ - supersaturation

P_i° - input partial pressure

P_i - equilibrium partial pressure



Experimental setup

Research goals

Goal 1: Find optimal parameters for HVPE- $\text{Al}_x\text{Ga}_{1-x}\text{N}$ growth (i.e. good morphology)

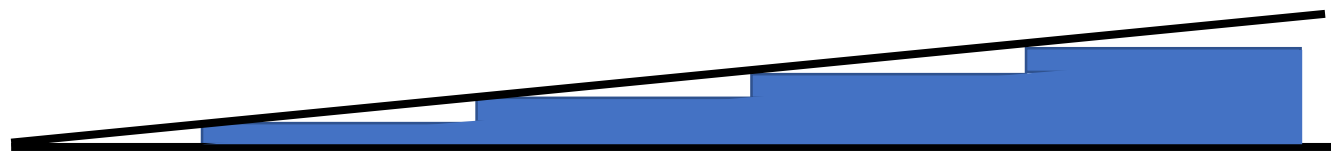
→ 2" Al_2O_3 templates (0.5 μm GaN layer) + final test on 2" Am-GaN

$$1. V/III = \frac{P_{\text{NH}_3}^\circ}{P_{\text{AlCl}_3}^\circ + P_{\text{GaCl}}^\circ}$$

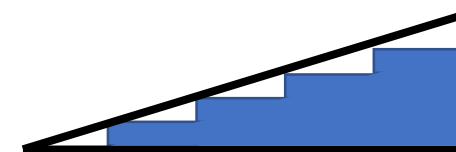
2. Total pressure

Goal 2: Analyze the influence of misorientation on $\text{Al}_x\text{Ga}_{1-x}\text{N}$ growth

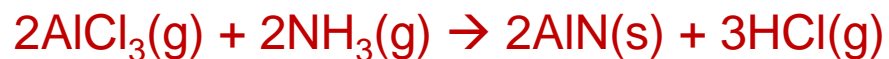
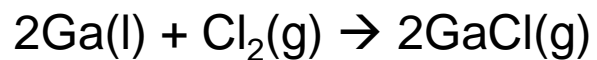
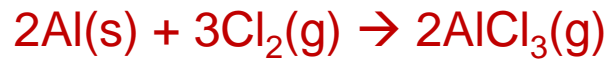
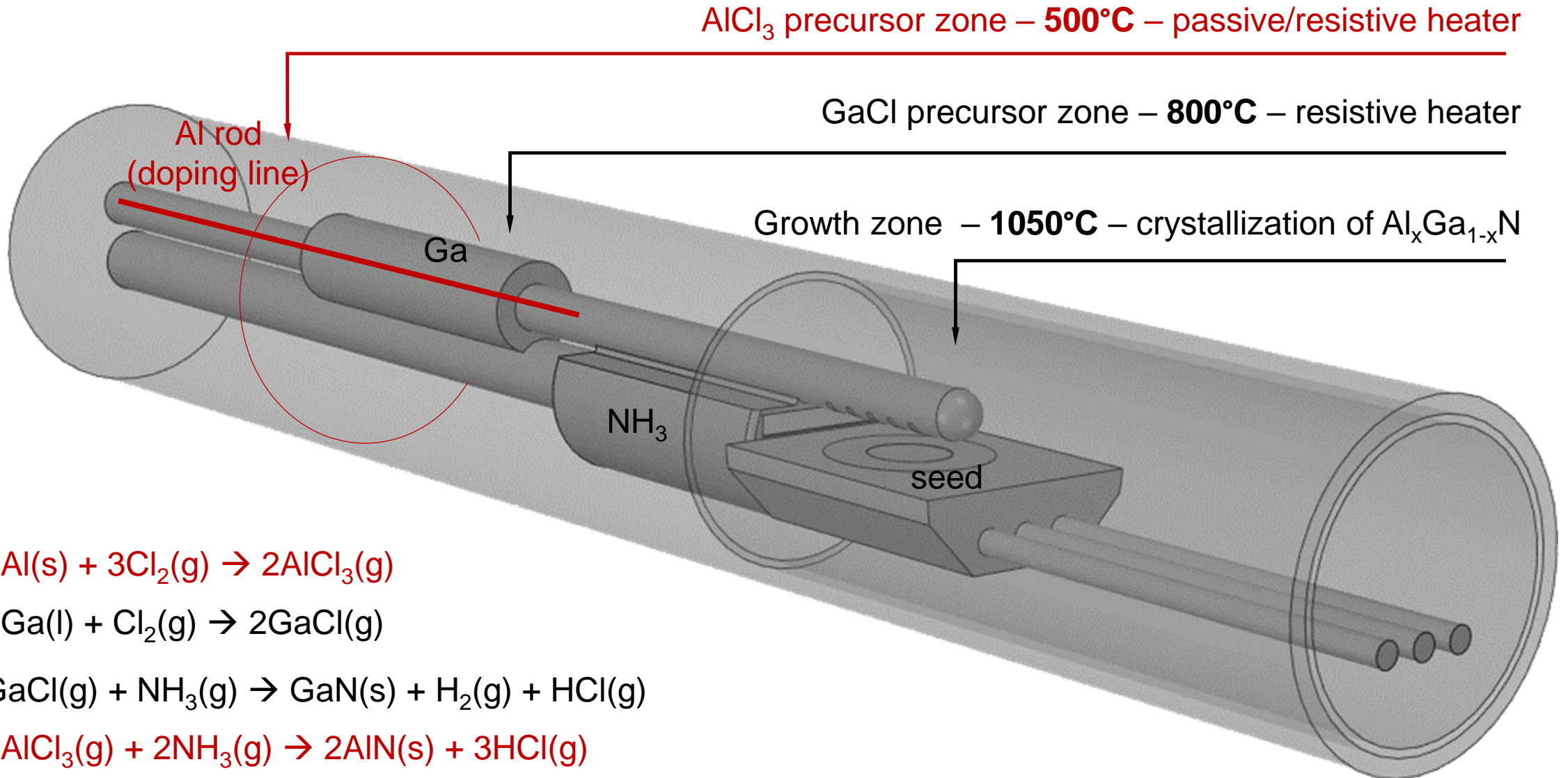
→ 4x 1" Am-GaN substrates (0.5°, 1°, 2°, 4° offcut relative to m-plane (10-10))



Low misorientation



High misorientation

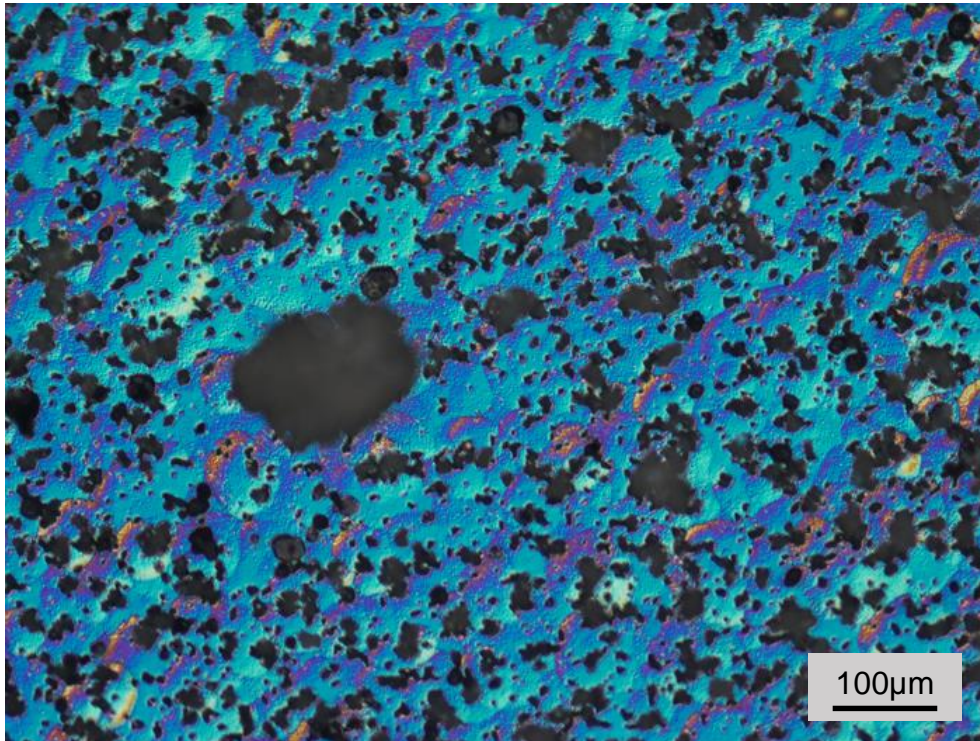




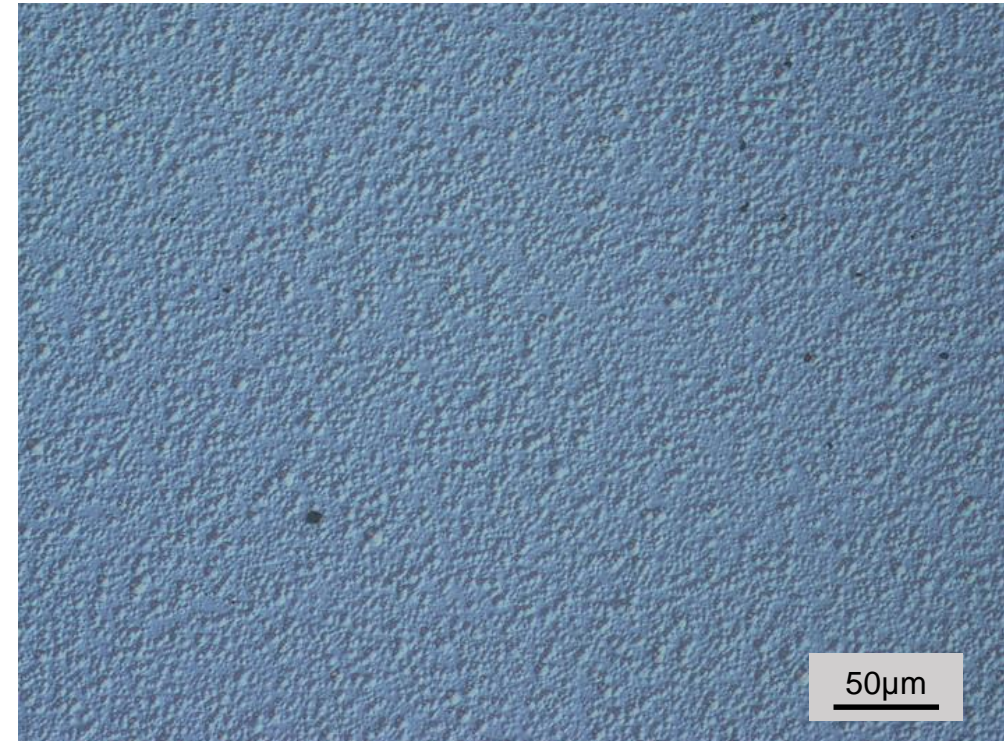
Results: Parameter optimization

$\text{Al}_x\text{Ga}_{1-x}\text{N}/\text{Al}_2\text{O}_3 - \text{V/III ratio (p = 800 mbar)}$

V/III = 59



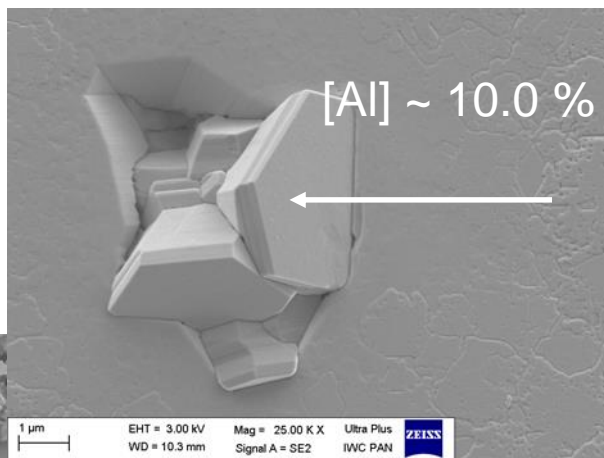
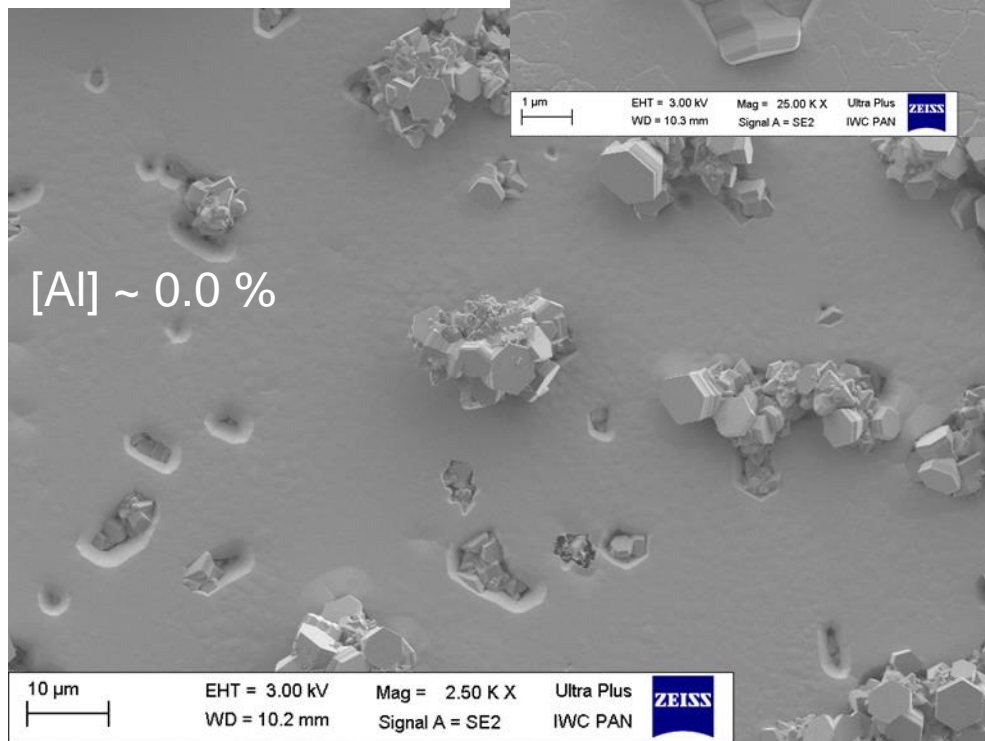
V/III = 21



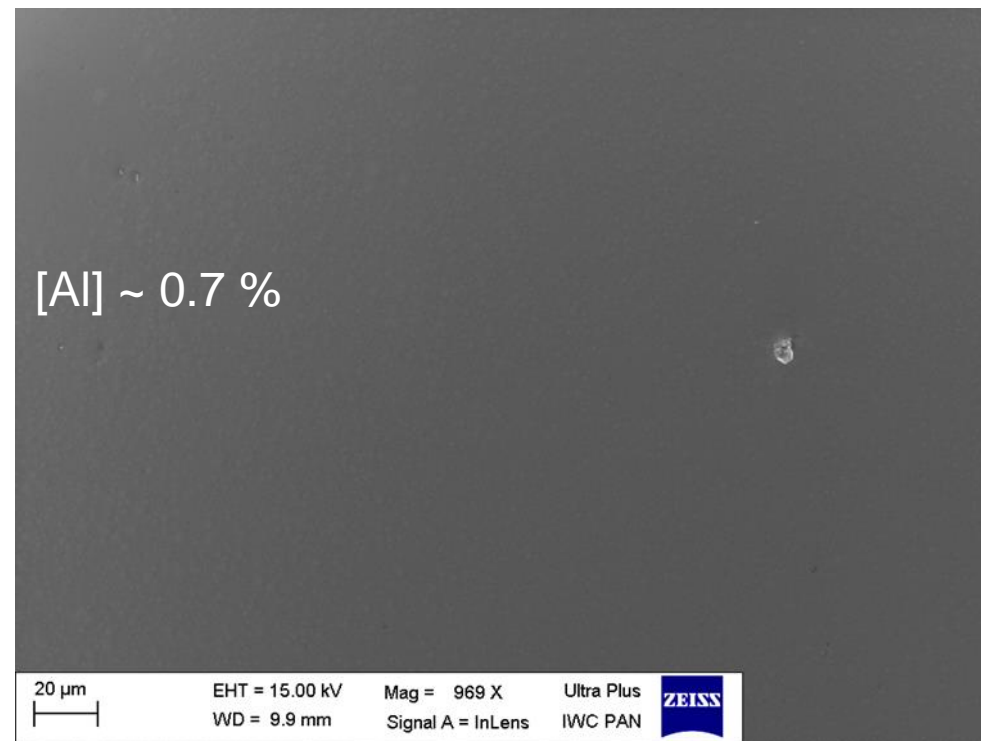
$$V/III = \frac{P_{\text{NH}_3}^\circ}{P_{\text{AlCl}_3}^\circ + P_{\text{GaCl}}^\circ}$$

$\text{Al}_x\text{Ga}_{1-x}\text{N}/\text{Al}_2\text{O}_3$ – V/III ratio ($p = 800$ mbar)

V/III = 59



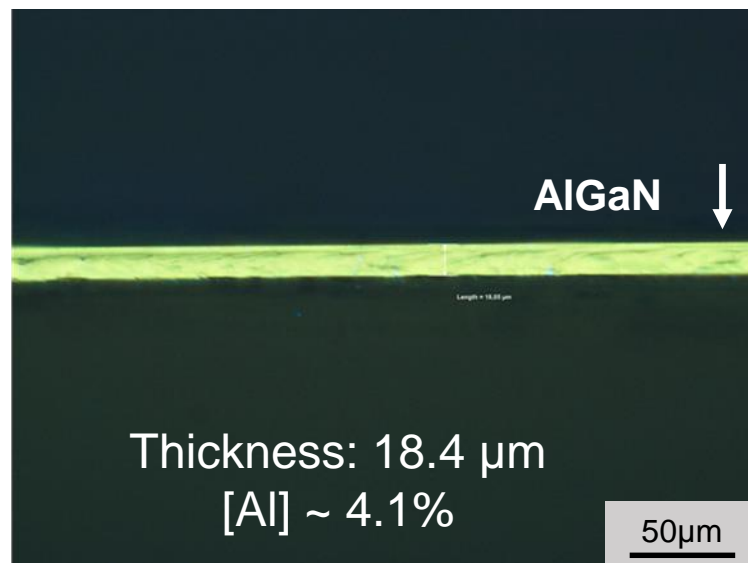
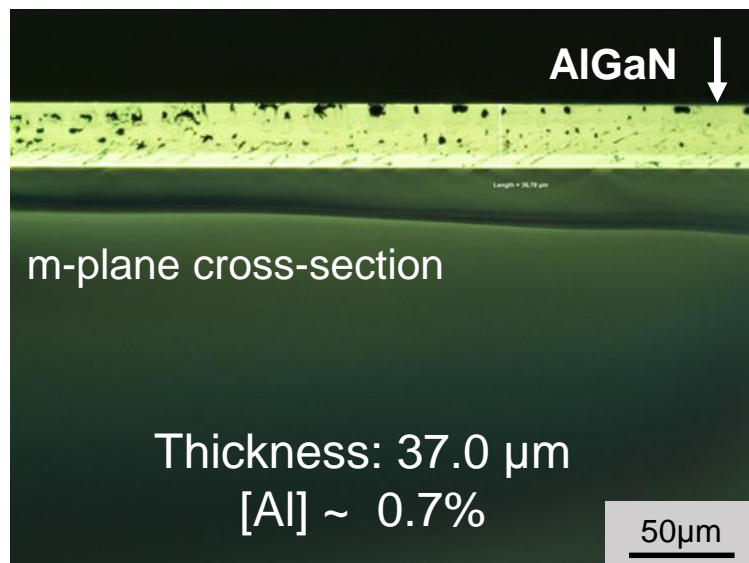
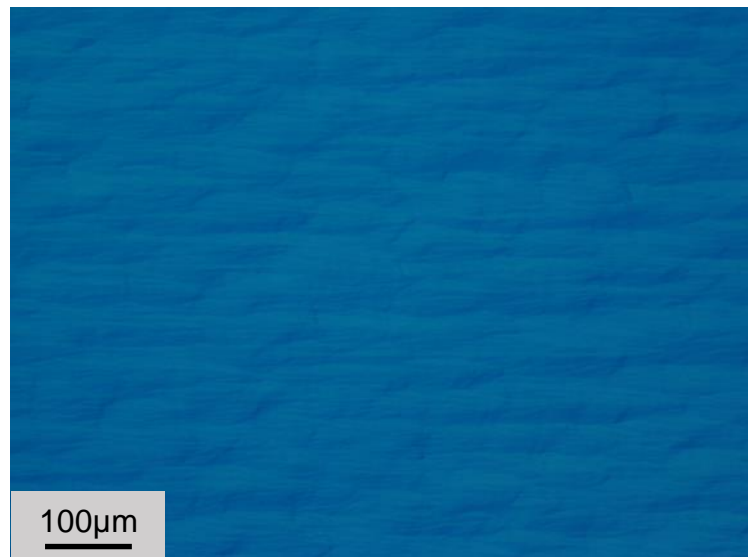
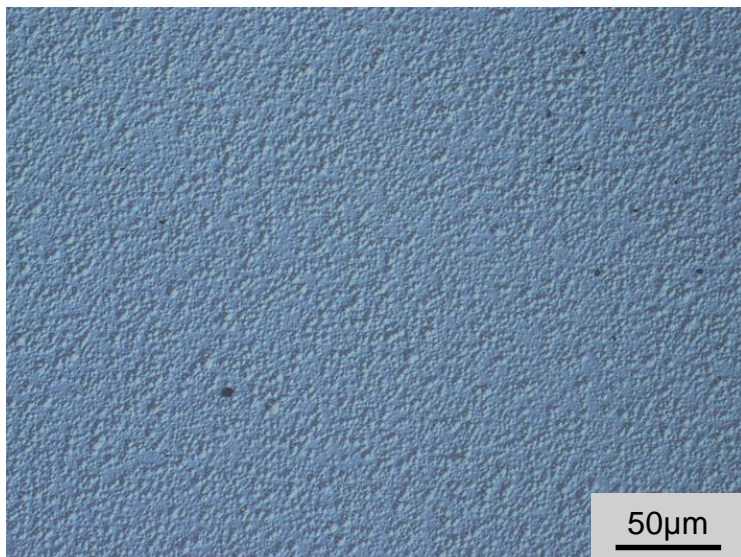
V/III = 21



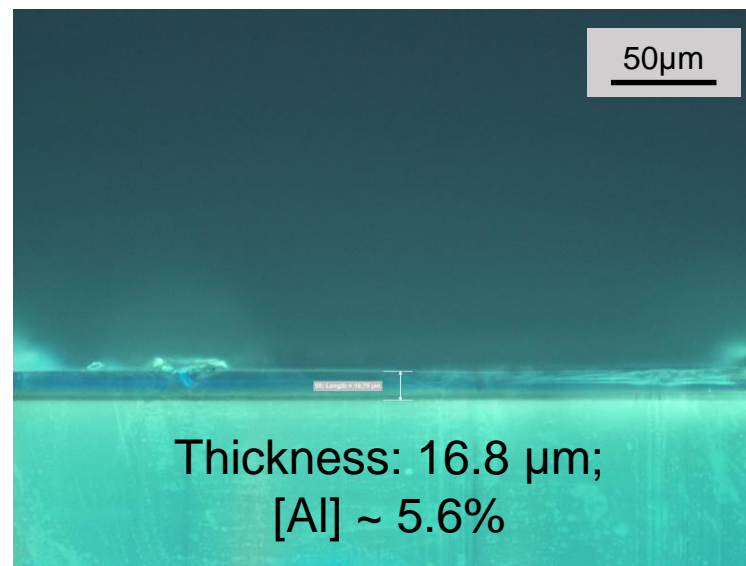
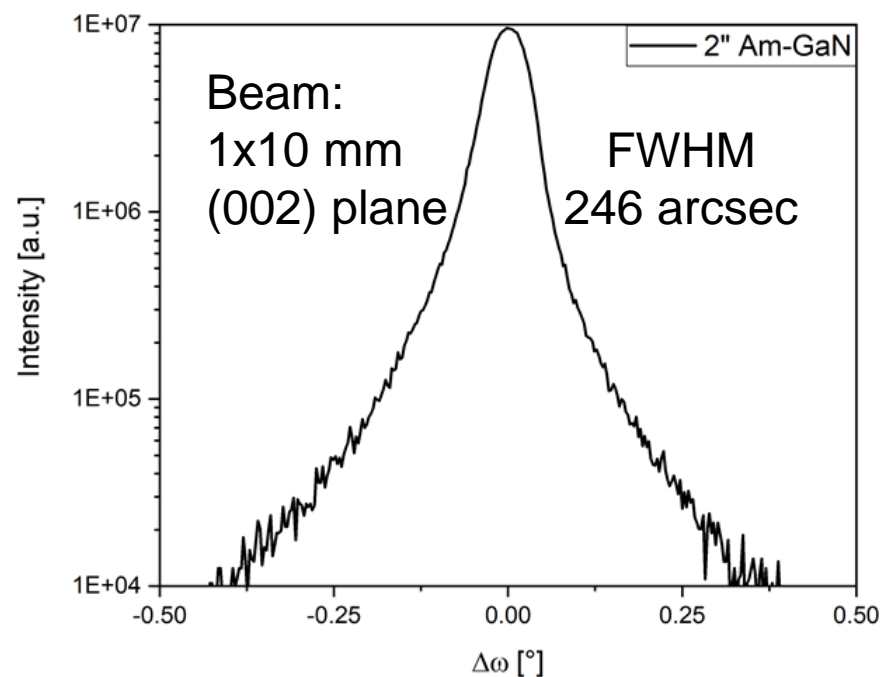
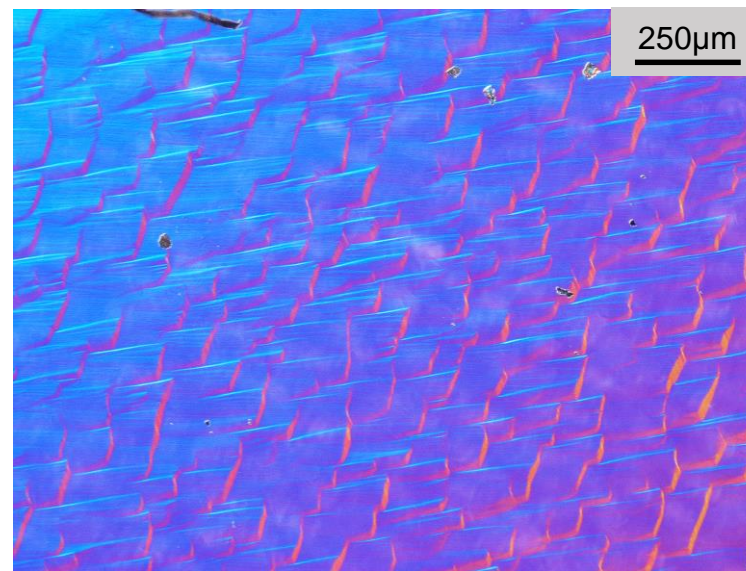
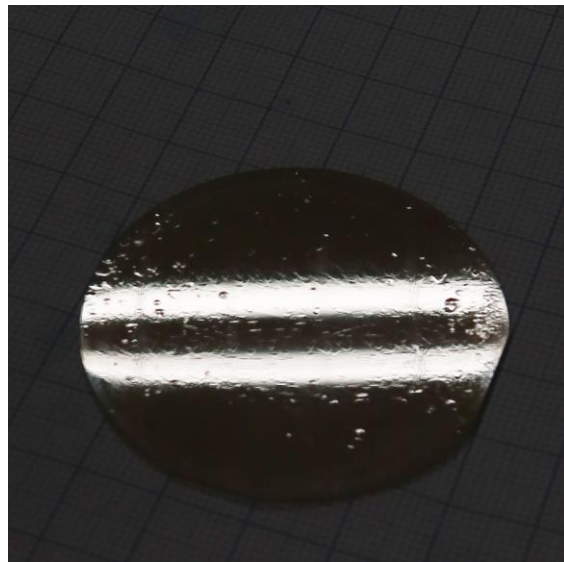
$\text{Al}_x\text{Ga}_{1-x}\text{N}/\text{Al}_2\text{O}_3$ – total pressure (V/III = 21)

800 mbar

200 mbar



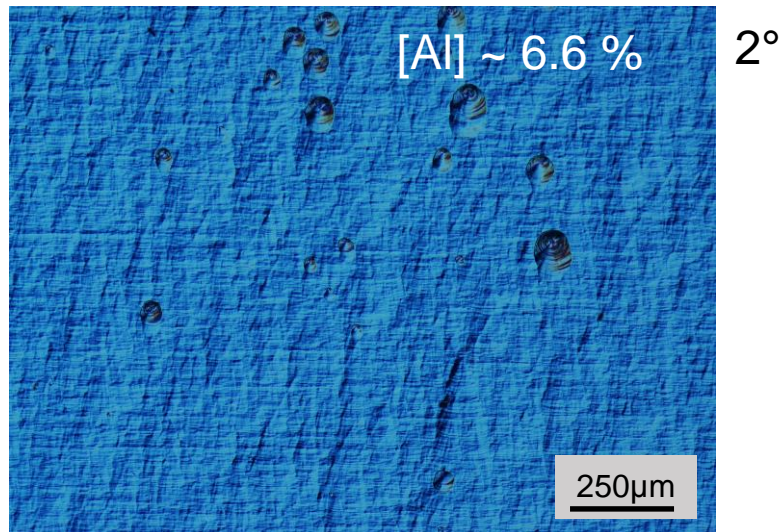
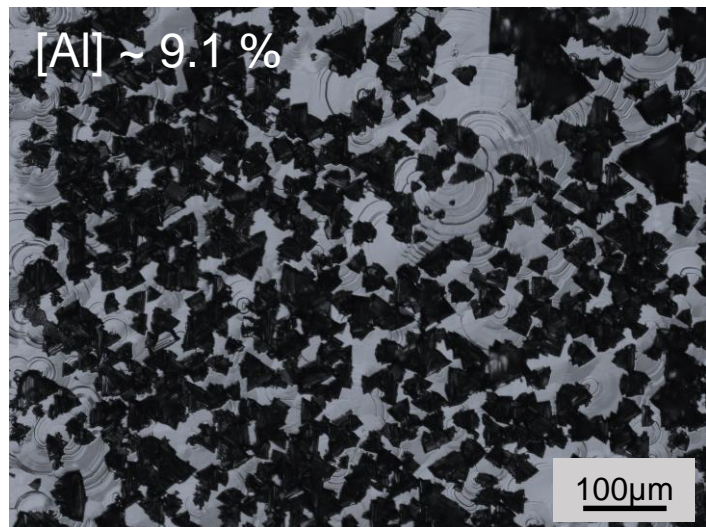
$\text{Al}_x\text{Ga}_{1-x}\text{N}$ on 2" Am-GaN ($p = 200 \text{ mbar}$, $V/\text{III} = 21$)





Results: Influence of misorientation

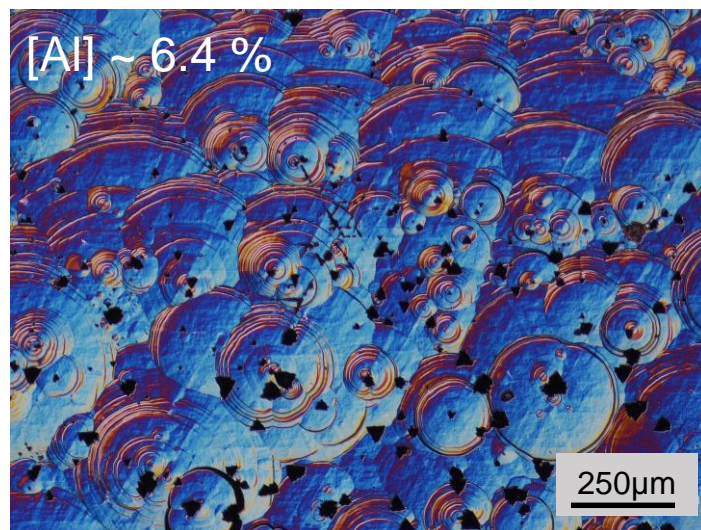
Misorientation (1" $\text{Al}_x\text{Ga}_{1-x}\text{N}/\text{Am-GaN}$)



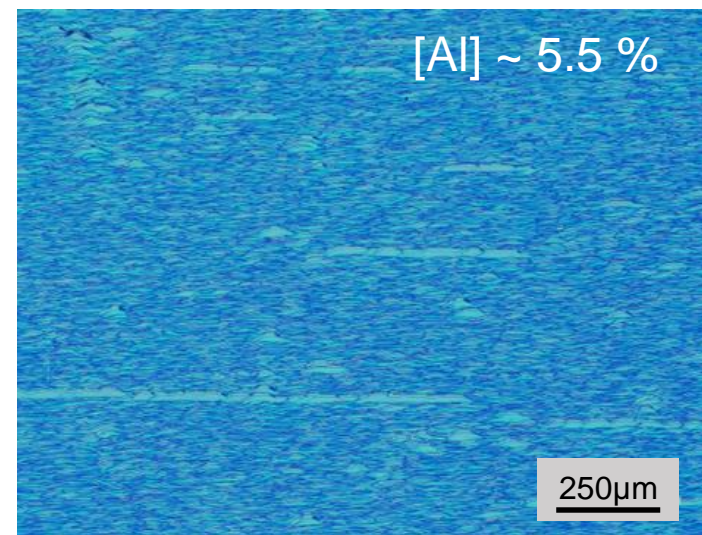
2°

4°

0.5°

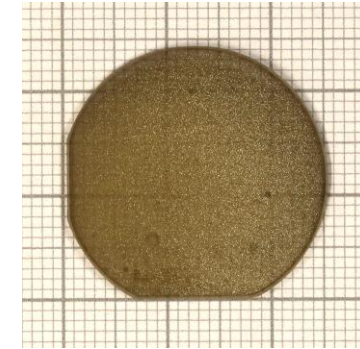
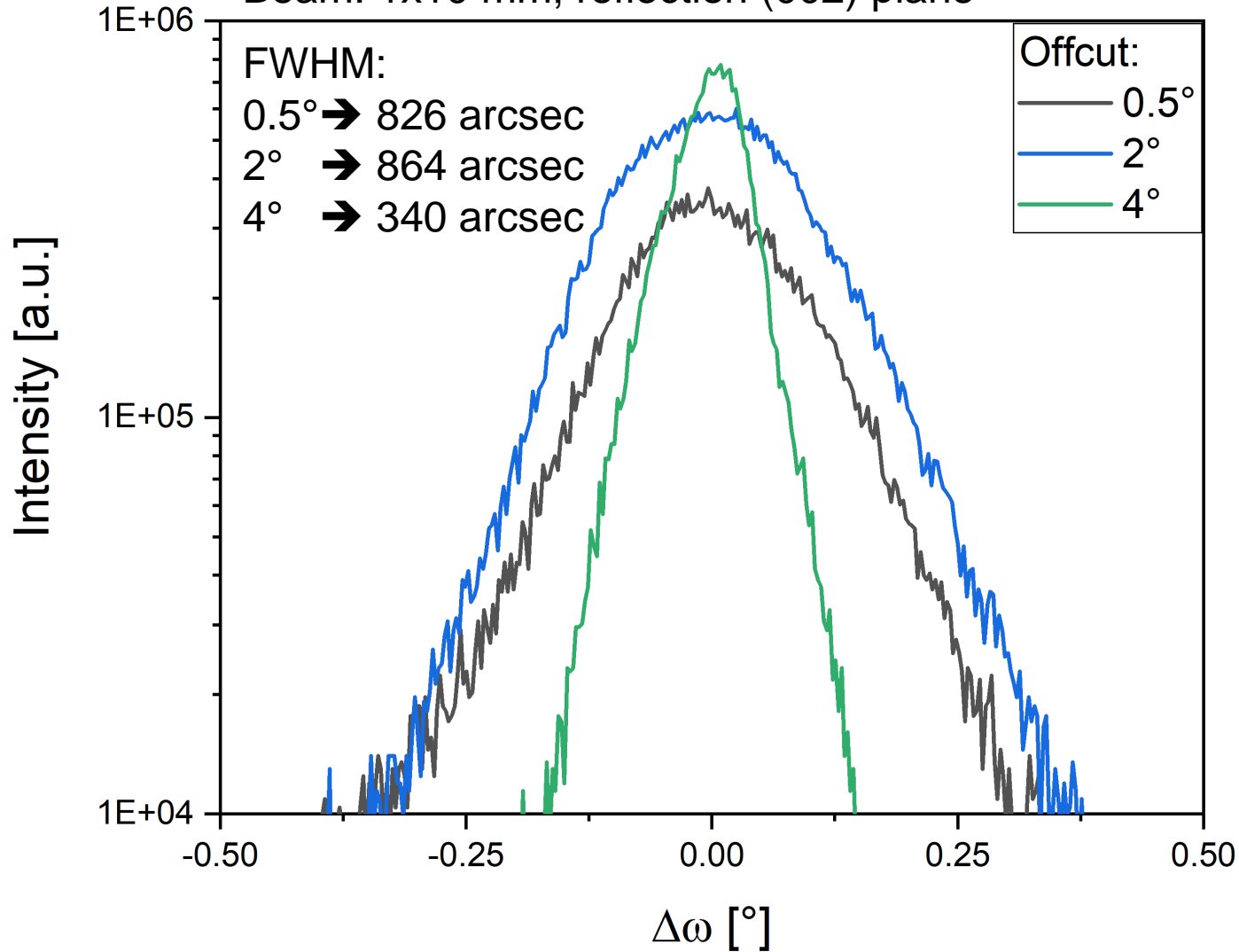


1°

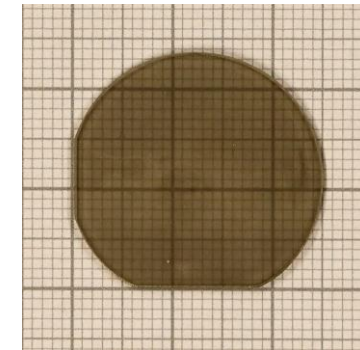


Misorientation (1" $\text{Al}_x\text{Ga}_{1-x}\text{N}/\text{Am-GaN}$)

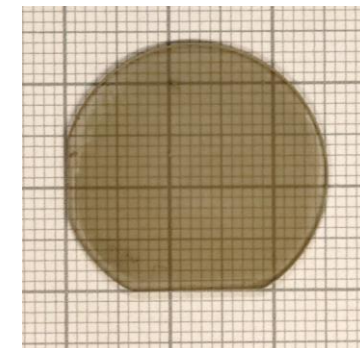
Beam: 1x10 mm; reflection (002) plane



0.5°



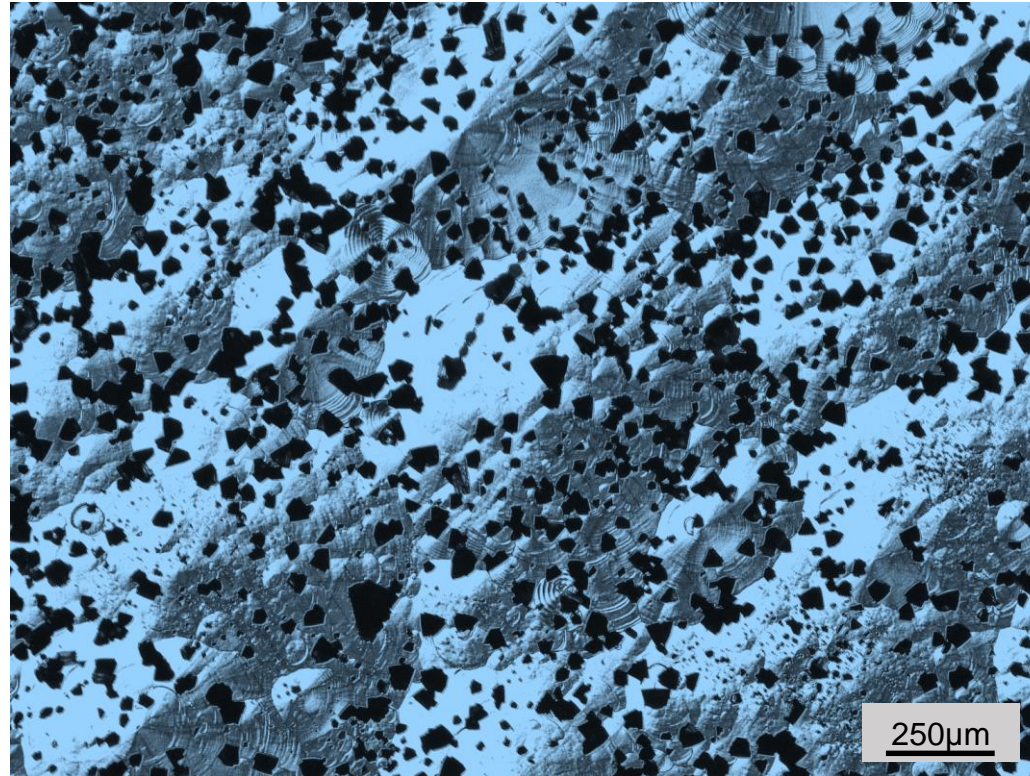
2°



4°

Current research: How to increase Al %? (H₂ admixture)

Problem 1: Low [Al] % (only 4%) → Solution 1: Add more Cl₂ over Al



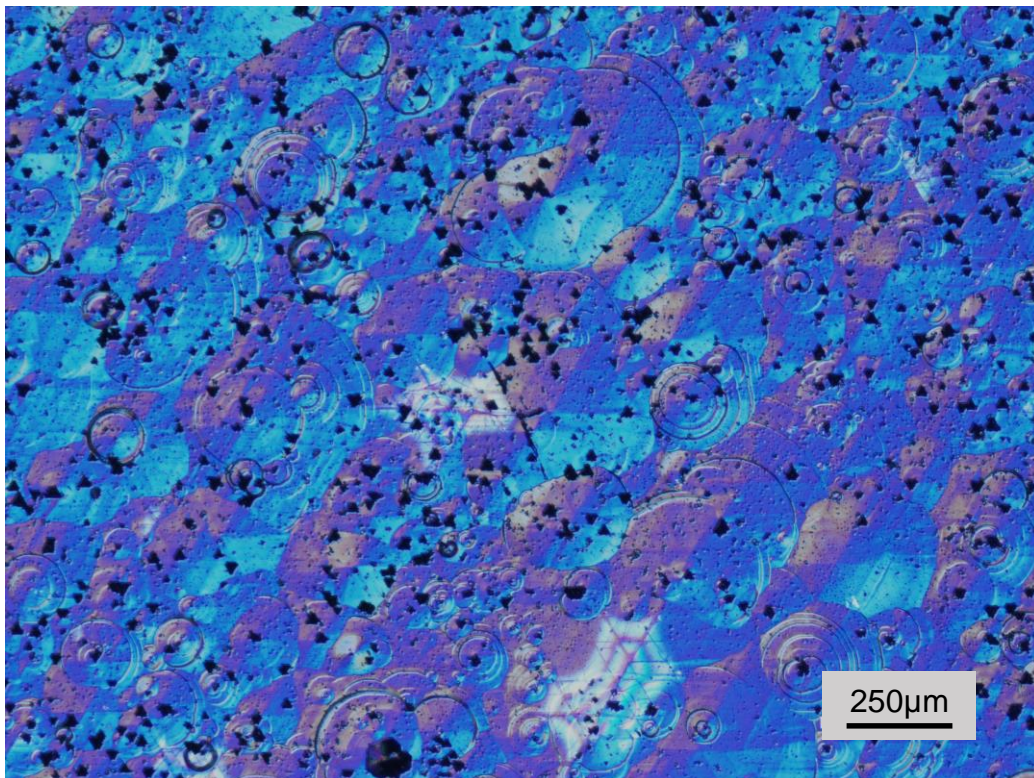
[Al] ~ 5.6 % (✓)

Crystallites (✗)

Current research: How to increase Al %? (H₂ admixture)

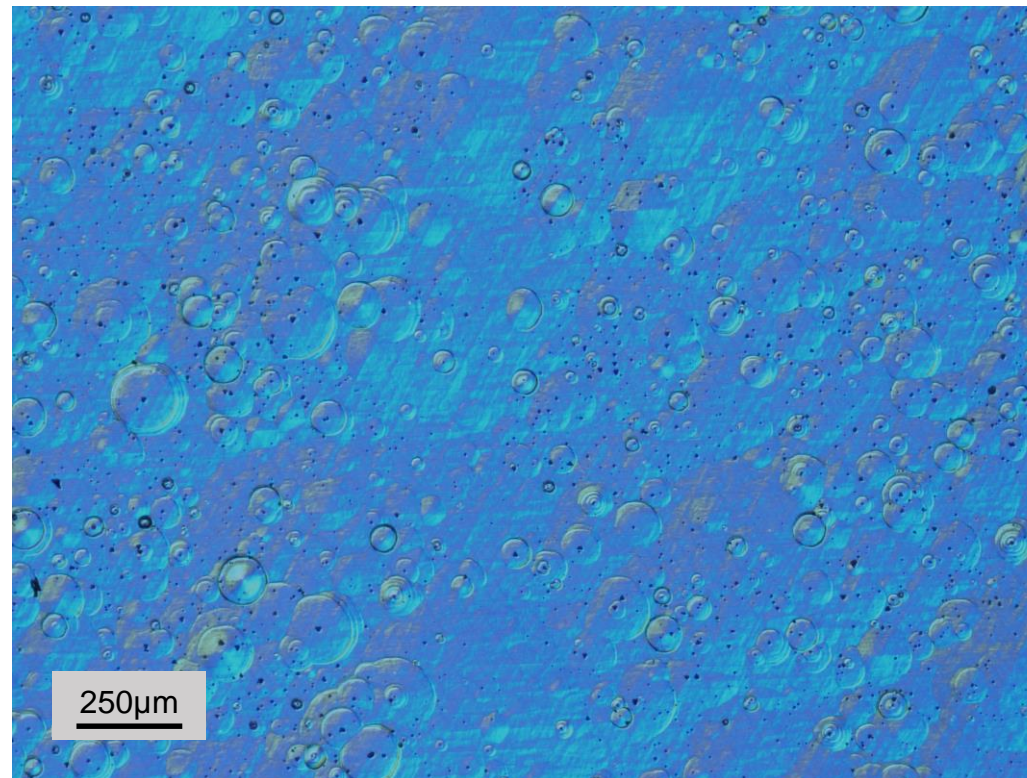
Problem 2: Crystallites → Solution 2: Add H₂

5% H₂ (95% N₂)



[Al] ~ 7.3 % (✓)
Crystallites (~)

10% H₂ (90% N₂)



[Al] ~ 8.5 % (✓)
Crystallites (✓)



Summary

Conclusions

- The most optimal $\text{Al}_x\text{Ga}_{1-x}\text{N}$ layers morphology was observed for growth in $p = 200 \text{ mbar}$ & $V/\text{III} = 21$
- Higher misorientation angle \rightarrow improvement of post-growth morphology & structural quality (XRD)
- The addition of H_2 admixture (5%, 10%) has increased Al incorporation in the grown layers

Next: Strain engineering to obtain a free-standing $\text{Al}_x\text{Ga}_{1-x}\text{N}$ crystal



Acknowledgments

Sonata Project – National Science Center
2020/39/D/ST5/01611

LIDER Project - National Centre for Research and Development
LIDER/23/0129/L-10/18/NCBR/2019





Thank you for your attention